Hybrid 8j89 Traveler

November 23, 1999

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J89 has die: 000-000 000-000 000-000 000-000 000-000 000-000 000-000 000-000

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j89 classification info. Created 19:42:37 11/19/99

Hybrid 8j89 quality: fair
Chip classification: good fair fair good good good good good
Bad channels (chip-channel): 2-110 2-111
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-23-1 1-24-1 1-37-1
   1-38-1 2-0-110 2-0-111 2-10-110 2-22-110 2-35-110 2-35-111 2-36-110
   2-39-110 2-39-111 2-40-110 2-42-110 2-42-111 2-44-110 2-44-111 2-9-109
   2-9-110 2-9-111
Channels at pedestal needed for DCMS: 35.6 36.6 33.6 33.7 35.6 33.7 35.7 34.7
```

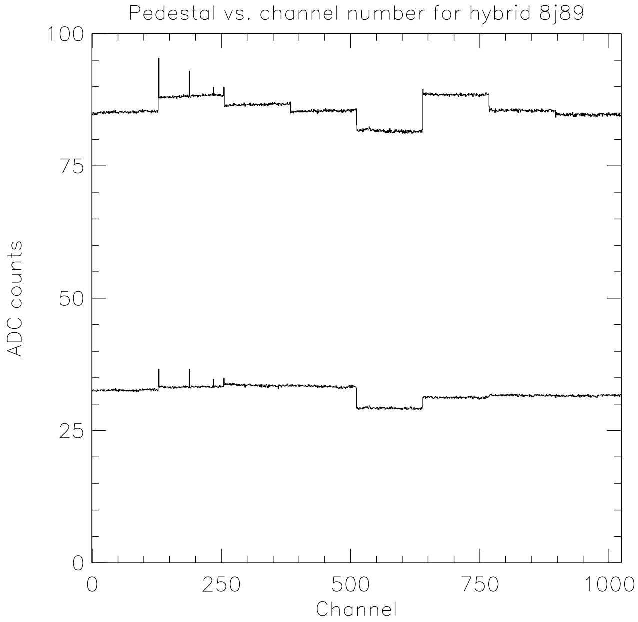
4 Comments

No comments.

5 Pedestal

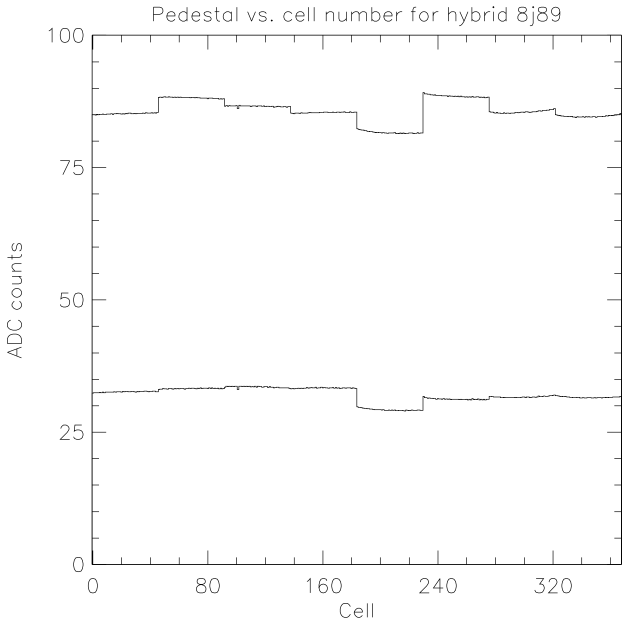
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

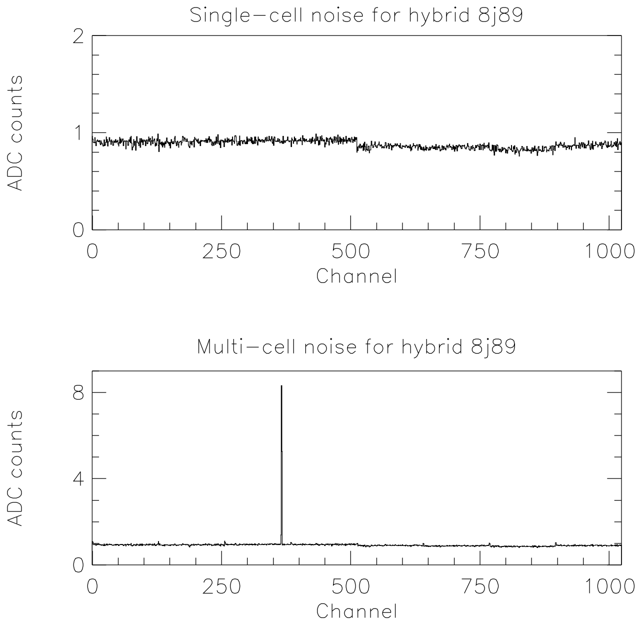
Pedestal vs. Pipeline Cell ID



6 Noise

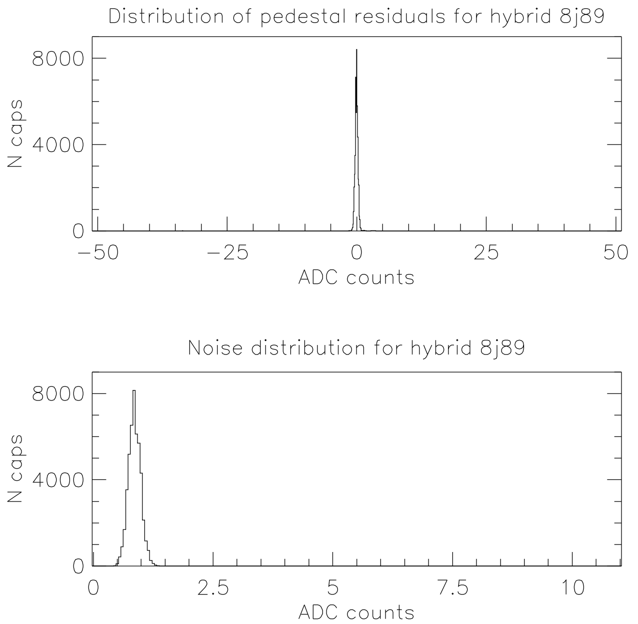
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in